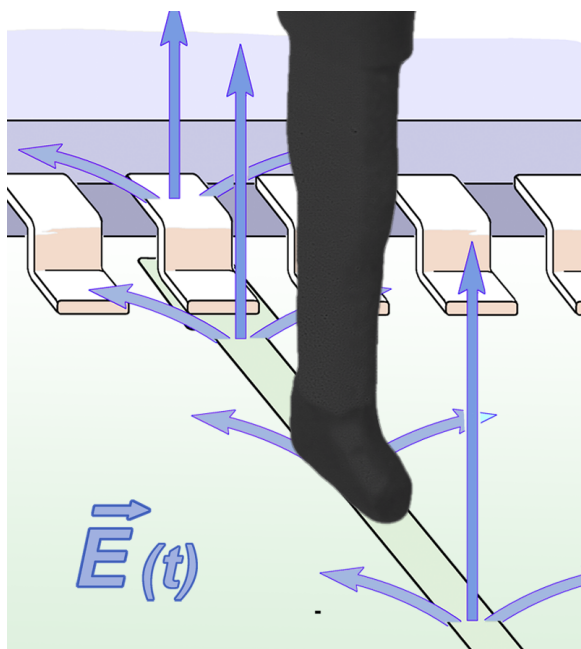


RF-E 05

E-Field Probe 30 MHz up to 3 GHz

LANGER
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Short description

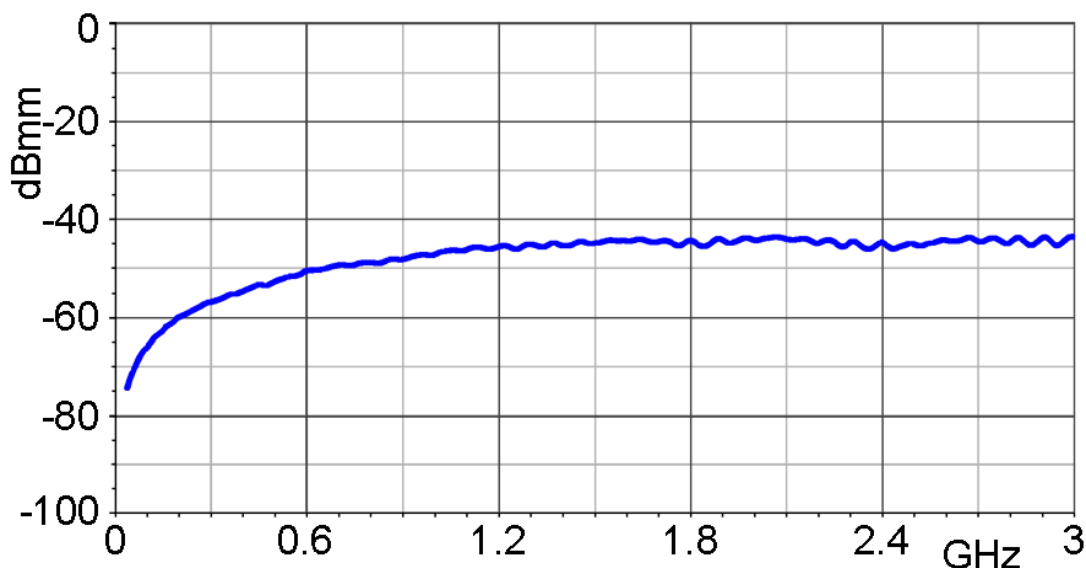
The electrode at the underside of the probe head of the RF-E 05 has a width of approx. 0.5 mm. The E-fields of clocked lines, IC pins, and smaller components are precisely located. The RF-E 05 probe was developed for Langer scanner.

The RF-E 05 is a near-field probe. It has the same structure as the RF-E 02 and RF-E 10 probes, but detects E-fields from very small ranges. The RF-E 05 is designed to detect the specific cause of an electrical interference field. For measurements the E-field probe is positioned directly onto or held above the components or surfaces of printed circuit boards. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

Frequency range	30 MHz ... 3 GHz
Resolution	≈ 0.6 mm
Probe head dimensions	$\approx (1 \times 8)$ mm
Connector - output	SMB, male, jack

Frequency response [dB μ V] / [dB μ V/mm]

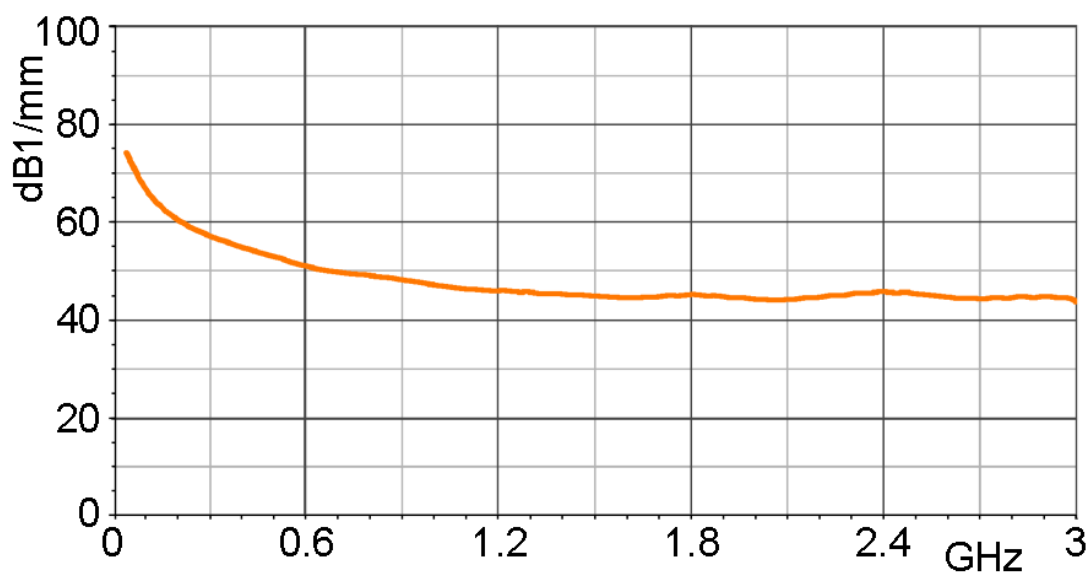


RF-E 05

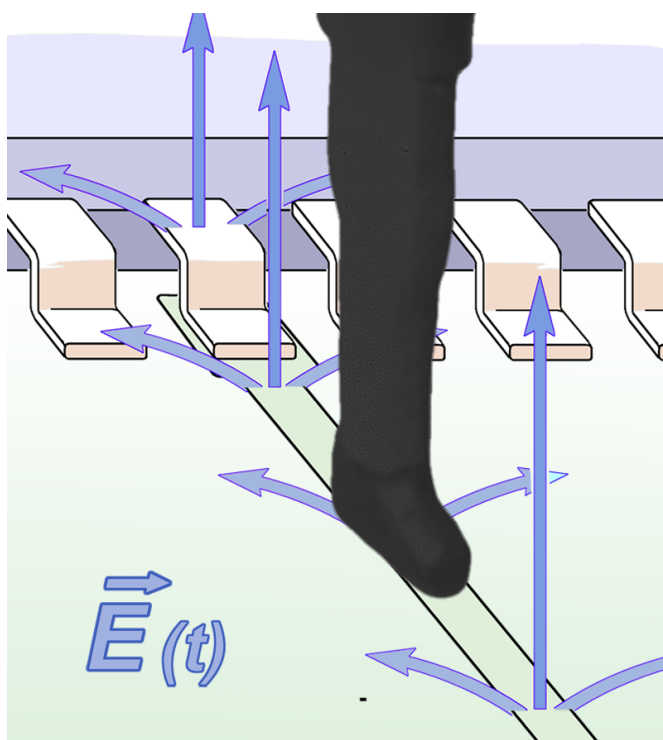
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E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 05

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Probe head

